

Search Notes

Application/Control No.

09/784,722

Examiner

Djenane M. Bayard

Applicant(s)/Patent under
Reexamination

TANG ET AL.

Art Unit

2141

SEARCHED

Class	Subclass	Date	Examiner
370	392	1/30/2006	DB
709	238	1/30/2006	DB
370	400	1/30/2006	DB

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
east	1/30/2006	DB